				<u> </u>
· P	FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. HIENER.1CPC1CP	APPLICATION NO. 09/883,851
	V-1	DISCLOSURE STATEMENT		
AIIA	AUG 3 0 2004	Y APPLICANT SHEETS IF NECESSARY)	APPLICANT Bogdan C. Maglich	
18			FILING DATE June 18, 2001	GROUP 3641
A	THAUCH			

			U.S. PATENT DOCUMENTS				
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE	
				<u> </u>			
				<u> </u>			
			· · · · · · · · · · · · · · · · · · ·	<u> </u>			
			·	1			
	· · · · · · · · · · · · · · · · · · ·		······································	 			
				 			
·	<u> </u>	<u> </u>		<u> </u>		·	. <u>.</u>
		·	FOREIGN PATENT DOCUMENTS		,		
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
INCLIAL			······································	 		YES	NO
-				 _		-	
	,			 		<u> </u>	
						•	
			· 	 			
				 		<u> </u>	
		<u> </u>					<u> </u>
XAMINER INITIAL	OT	HER DOCUME	NTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT	PAGES,	ETC.)		
	Beyerle, Albert, et al., De Research A299 (1990), p	sign of an a p. 458-462.	ssociated particle imaging system, <u>Nuclear</u>	Instrum	ents and Me	ethods in	Physic
				<u>-</u>			
	,						

082604

EXAMINER

DATE CONSIDERED

'EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.